

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. NIT-163-02	SERIAL NO. 10/075,283
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT M. IWAYAMA et al	
		FILING DATE February 15, 2002	GROUP 2175

U.S. PATENT DOCUMENTS

* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
AA	5,590,319	12/31/96	Cohen et al			
AB	5,987,460	11/1999	Niwa et al			
AC	5,926,811	07/1999	Miller et al			
AD	5,870,740	02/1999	Miller et al			
AE						
AF						
AG						
AH						
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AJ						
AK						

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FOREIGN PATENT DOCUMENTS

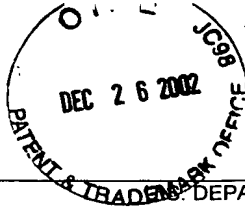
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AL	64-74210	03/20/89	Japan			<input type="checkbox"/>	<input type="checkbox"/>
AM	93/37499	08/27/98	WO PCT			<input type="checkbox"/>	<input type="checkbox"/>
AN	10-74210	03/17/98	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
AO	11-85786	03/30/99	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
AP	10-254887	09/25/98	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

AR	B. Velez et al, "Fast and Effective Query Refinement", Annual International ACM-SIGIR Conference on Research and Development in Information Retrieval, US, New York, NY, July 27, 1997, pp. 6-15.
AS	
AT	

EXAMINER	DATE CONSIDERED
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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	AK							
FOREIGN PATENT DOCUMENTS								
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	8-287103	11/01/96	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
	AM	9-62693	03/07/97	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
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	AO						<input type="checkbox"/>	<input type="checkbox"/>
	AP						<input type="checkbox"/>	<input type="checkbox"/>
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